PCN Number:		201	20140115002				PCN Date: 01/22/20		01/22/2014		
Title	Qualification of Cu as Alternative Wire Base Metal for Selected Device(s)										
Customer Contact:		PCN	PCN Manager		Phone	::	+1(214)480-6037		Dept: Qua		uality Services
Proposed 1 st Ship I		p Date		04/22/201	.4	Estimated Sample Ava				ate provided at mple request	
Cha	nge Type:										
\boxtimes	Assembly Site	е		Assemb	ly Proce	SS		\boxtimes	Assembly M	1ate	erials
	Design			Electrica	al Specif	ica	tion		Mechanical	Spe	ecification
\boxtimes	Test Site			Packing	/Shippir	ıg/L	abeling		Test Proces		
	Wafer Bump	Site		Wafer B	Wafer Bump Material			Wafer Bump Process		rocess	
Wafer Fab Site		Wafer F	Wafer Fab Materials			Wafer Fab Process					
Part number ch			ang	je			,				
	PCN Details										

Description of Change:

Texas Instruments is pleased to announce the qualification of Cu as an additional bond wire option for devices listed in "Product affected" section below. Material differences are shown in the following table:

Group 1 Device: Devices will remain in current assembly facility

	From	То
Wire type	Au	Cu
Mold Compound	R-13	R-17
Leadframe Finish	NiPdAu	Matte Sn

Upon expiration of this PCN, TI will combine lead free solutions in a single <u>standard part number</u>, for example; <u>SN001066DBVR</u> – can ship with both Matte Sn and NiPdAu.

Group 2 Device: MLA as additional Assembly and Test Site

	CAR	MLA
Wire type	Au	Cu
Mold Compound	438578	4206193

Test coverage, insertions, conditions will remain consistent with current testing and verified with test MQ.

Reason for Change:

Continuity of supply.

- 1) To align with world technology trends and use wiring with enhanced mechanical and electrical properties
- 2) Maximize flexibility within our Assembly/Test production sites.
- 3) Cu is easier to obtain and stock

Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):

None.

Changes to product identification resulting from this PCN:

Group 1 Device: Devices will remain in current assembly facility

ECAT: G4 = NiPdAu ECAT: G3 = Matte Sn

Assembly Site

NFME	Assembly Site Origin (22L)	ASO:NFME	ECAT:G4
NFME	Assembly Site Origin (22L)	ASO: NFME	ECAT:G3

Sample product shipping label to show code location only (not actual product label)



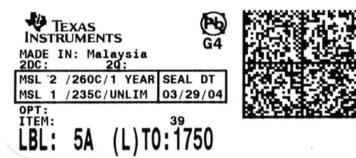
(1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483\$I2 (P) (2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO: USA (22L) ASO: MLA (23L) ACO: MYS

Group 2 Device: CAR to MLA

Assembly Site		
CARSEM Malaysia	Assembly Site Origin (22L)	ASO: CAR
TI Malaysia	Assembly Site Origin (22L)	ASO: MLA

ASSEMBLY SITE CODES: CAR = V, MLA = K

Sample product shipping label (not actual product label)



(1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T) LOT: 3959047MLA (4W) TKY (1T) 7523483\$I2 (P) (2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACO: MYS

Product Affected: Group 1 Device						
SN001066DBVR	SN74AHCT1G04DBVT	SN74AUP1G17DBVT	SN74LVC1G332DBVR			
SN003166DBVR	SN74AHCT1G08DBVR	SN74AUP1G97DBVR	SN74LVC1G79DBVR			
SN74AHC1G02DBVR	SN74AHCT1G08DBVT	SN74CB3T1G125DBVR	SN74LVC1G79DBVT			
SN74AHC1G02DBVT	SN74AHCT1G125DBVR	SN74LVC1G00DBVR	SN74LVC1G80DBVR			
SN74AHC1G04DBVR	SN74AHCT1G125DBVT	SN74LVC1G00DBVT	SN74LVC1G80DBVT			
SN74AHC1G04DBVT	SN74AHCT1G126DBVR	SN74LVC1G02DBVR	SN74LVC1G86DBVR			
SN74AHC1G08DBVR	SN74AHCT1G126DBVT	SN74LVC1G02DBVT	SN74LVC1G86DBVT			
SN74AHC1G08DBVT	SN74AHCT1G32DBVR	SN74LVC1G06DBVR	SN74LVC1GU04DBVR			
SN74AHC1G09DBVR	SN74AHCT1G32DBVT	SN74LVC1G06DBVT	SN74LVC1GU04DBVT			
SN74AHC1G125DBVR	SN74AHCT1G86DBVR	SN74LVC1G07DBVR	SN74LVC2G04DBVR			
SN74AHC1G125DBVT	SN74AHCT1G86DBVT	SN74LVC1G07DBVT	SN74LVC2G04DBVT			
SN74AHC1G126DBVR	SN74AUC1G00DBVR	SN74LVC1G11DBVR	SN74LVC2G07DBVR			
SN74AHC1G126DBVT	SN74AUC1G07DBVR	SN74LVC1G126DBVR	SN74LVC2G14DBVR			
SN74AHC1G32DBVR	SN74AUC1G07DBVT	SN74LVC1G126DBVT	SN74LVC2G14DBVT			
SN74AHC1G32DBVT	SN74AUC1G14DBVR	SN74LVC1G14DBVR	SN74LVC2G17DBVR			
SN74AHC1G86DBVR	SN74AUC1G17DBVR	SN74LVC1G14DBVT	SN74LVC2G17DBVT			
SN74AHC1G86DBVT	SN74AUC1G32DBVR	SN74LVC1G17DBVR	SN74LVC2G34DBVR			
SN74AHC1GU04DBVR	SN74AUC1G66DBVR	SN74LVC1G17DBVT	SN74LVC2G34DBVT			
SN74AHC1GU04DBVT	SN74AUC2G07DBVR	SN74LVC1G240DBVR	TS5A1066DBVR			
SN74AHCT1G00DBVR	SN74AUP1G04DBVR	SN74LVC1G240DBVT	TS5A3166DBVR			
SN74AHCT1G00DBVT	SN74AUP1G04DBVT	SN74LVC1G27DBVR	TS5A3167DBVR			
SN74AHCT1G02DBVR	SN74AUP1G07DBVR	SN74LVC1G3157DBVR	TS5A63157DBVR			
SN74AHCT1G02DBVT	SN74AUP1G08DBVR	SN74LVC1G32DBVR				
SN74AHCT1G04DBVR	SN74AUP1G17DBVR	SN74LVC1G32DBVT				
Product Affected: Group	2 Device					
UCC3895PW	UCC3895PWG4	UCC3895PWTR	UCC3895PWTRG4			

Qualification Data: Group 1						
This qualification has been developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.						
Qual Vehicle 1: TL432ACDBVR (MSL 1-260C)						
	Package Construction Details					
Assembly Site:	NFME	Mold Compound:	R-17			
# Pins-Designator, Family: 5-DBV, SOT-23 Mount Compound: A-03						
Lead frame (Finish, Base):	Matte Sn, Cu	Bond Wire:	1.0 Mil Dia., Cu			

Qualification: Plan	Test Results				
	C 1:::		San	nple Size/	'Fail
Reliability Test	Conditions		Lot# 1	Lot# 2	Lot# 3
Electrical Characterization	-		Pass	-	-
**Unbiased HAST	130C/85%RH/3	3.3 psia (96 hrs)	77/0	77/0	77/0
**T/C -65C/150C	-65C/+150C (5		77/0	77/0	77/0
**High Temp. Storage Bake	170C (600 hrs)	, ,	77/0	77/0	77/0
**Autoclave	121C (192 hrs)		77/0	77/0	77/0
**Biased HAST	130C/85%RH (192 hrs)	77/0	77/0	77/0
**Life Test	150C (300 hrs)		77/0	77/0	77/0
Solderability		ours; PB-Free solder	22/0	22/0	22/0
X-ray	(top side only)		5/0	5/0	5/0
Flammability	(IEC 695-2-2)		5/0	5/0	-
Flammability	(UL-1694)		5/0	5/0	-
Flammability	UL 94V-0)		5/0	5/0	-
Manufacturability (Assembly)	(per mfg. Site s	pecification)	Pass	Pass	Pass
Moisture Sensitivity	(level 1 @ 2600	12/0	12/0	12/0	
Notes **- Preconditioning se				•	
		21IDBVR (MSL 1-260C)			
		struction Details			
Assembly Site: N	IFME	Mold Compound:	R-17		
# Pins-Designator, Family: 5	5-DBV, SOT-23	Mount Compound:	A-03		
Lead frame (Finish, Base): N	latte Sn, Cu	Bond Wire:	1.0 Mil	Dia., Cu	
Qualification: Plan	Test Results				
Dolinbility Took	Conditions		Sample Size/Fail		
Reliability Test			Lot# 1	Lot# 2	Lot# 3
Electrical Characterization	-		Pass	-	-
**Unbiased HAST	130C/85%RH/3	3.3 psia (192 hrs)	77/0	77/0	77/0
**T/C -65C/150C	-65C/+150C (500 Cyc)		77/0	77/0	77/0
**High Temp. Storage Bake	170C (600 hrs)		77/0	77/0	77/0
**Autoclave	121C (192 hrs)		77/0	77/0	77/0
**Life Test	150C (300 hrs)		77/0	-	-
Solderability	Steam age, 8 hours; PB-Free solder		22/0	-	-
X-ray	(top side only)		5/0	5/0	5/0
Flammability	(IEC 695-2-2)		5/0	-	-
Flammability	(UL-1694)		5/0	-	-
Flammability	UL 94V-0)		5/0	-	-
Manufacturability (Assembly)	(per mfg. Site s	pecification)	Pass	Pass	Pass
Moisture Sensitivity	(level 1 @ 2600	peak +5/-0C)	12/0	12/0	12/0
Notes **- Preconditioning sec	guence: Level 1-2	160C.	-		

Qual Vehicle 3: INA193AIDBVR (MSL 2-260C)							
Package Construction Details							
Assembly Site:	NFME	Mold Compound:	R-17				
# Pins-Designator, Family:	5-DBV, SOT-23	Mount Compound:	A-03				
Lead frame (Finish, Base):	Matte Sn, Cu	Bond Wire:	1.0 Mil Dia.,	Cu			
Qualification:	☐ Test Results						
Deliability Test	Conditions		Sample S	Size/Fail			
Reliability Test	Conditions		Lot# 1	Lot# 2			
Electrical Characterization	-		10/0	-			
**Unbiased HAST	130C/85%RH/3	3.3 psia (96 hrs)	77/0	77/0			
**Biased HAST	130C/85%RH (192 hrs)	77/0	77/0			
**T/C -65C/150C	-65C/+150C (5	00 Cyc)	77/0	77/0			
**High Temp. Storage Bake	150C (500 hrs)		77/0	77/0			
Manufacturability (Assembly)	(per mfg. Site s	pecification)	Pass	Pass			
Moisture Sensitivity	(level 2 @ 2600		12/0	12/0			
Notes **- Preconditioning s	equence: Level 2-2	260C.					
Qual	Qual Vehicle 4: TMP121AIDBVR (MSL 2-260C)						
	Package Cor	struction Details					
Assembly Site:	NFME	Mold Compound:	R-17				
# Pins-Designator, Family:	6-DBV, SOT-23	Mount Compound:	A-03				
Lead frame (Finish, Base):	Matte Sn, Cu Bond Wire:		1.0 Mil Dia., Cu				
Qualification: Plan	☐ Test Results						
Reliability Test	Conditions	Conditions		Size/Fail			
Reliability Test	Conditions		Lot# 1	Lot# 2			
Electrical Characterization	-		10/0	-			
**Unbiased HAST	130C/85%RH/3	3.3 psia (96 hrs)	77/0	77/0			
**Biased HAST	130C/85%RH (192 hrs)	77/0	77/0			
**T/C -65C/150C	00 Cyc)	77/0	77/0				
**High Temp. Storage Bake	150C (500 hrs)		77/0	77/0			
X-ray	(top side only)		5/0	5/0			
Manufacturability (Assembly)	(per mfg. Site s	pecification)	Pass	Pass			
Moisture Sensitivity	(level 2 @ 2600		12/0	12/0			
Notes **- Preconditioning s	equence: Level 2-2	60C.					

Qual Vehicle 5: TPD4E001DBVR (MSL 1-260C)								
Package Construction Details								
Assembly Site:	NFME	Mold Compound:	R-17	R-17				
# Pins-Designator, Family:	6-DBV, SOT-23	Mount Compound:	A-03					
Lead frame (Finish, Base):	Matte Sn, Cu	Bond Wire:	1.0 Mil	Dia., Cu				
Qualification: Plan	☐ Test Results							
Reliability Test	Conditions	Conditions		Sample Size/Fail				
Reliability Test	Conditions		Lot# 1	Lot# 2	Lot# 3			
**Unbiased HAST	130C/85%RH/3	130C/85%RH/33.3 psia (192 hrs)			77/0			
**Biased HAST	130C/85%RH (130C/85%RH (192 hrs)			77/0			
**T/C -65C/150C	-65C/+150C (1	000 Cyc)	77/0	77/0	77/0			
**High Temp. Storage Bake	150C (1000 hrs	5)	77/0	77/0	-			
X-ray	(top side only)	(top side only)		5/0	5/0			
Manufacturability (Assembly)	y (Assembly) (per mfg. Site specification)			Pass	Pass			
Moisture Sensitivity (level 1 @ 260C peak +5/-0C) 12/0			12/0	12/0				
Notes **- Preconditioning s	equence: Level 1-2	260C.						

Qualification Data: Group 2

This qualification has been developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.							
Qua	al Vehicle 1: BQ	29330DBT (MSL 2-260C))				
	Package Cor	nstruction Details	_				
Assembly Site:	MLA	Mold Compound:	420619	93			
# Pins-Designator, Family:	30-DBT, TSSOP	Mount Compound:	404250	00			
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wire:	0.96 M	il Dia., Cι	J		
Qualification: Plan	Qualification: Plan Test Results						
Deliability Test	Conditions	Conditions		Sample Size/Fail			
Reliability Test	Conditions			Lot# 2	Lot# 3		
Electrical Characterization	-		Pass	-	-		
**T/C -65C/150C	-65C/+150C (500 Cyc)		77/0	77/0	77/0		
** Thermal Shock -65/150C	-65C/+150C (5	-65C/+150C (500 Cyc)		77/0	77/0		
**High Temp. Storage Bake	170C (420 hrs)	170C (420 hrs)		77/0	77/0		
**Autoclave	121C (96 hrs)	121C (96 hrs)		77/0	77/0		
Manufacturability (Assembly)		(per mfg. Site specification)		Pass	Pass		
Notes **- Preconditioning s	equence: Level 2-2	260C.					

Qual Vehicle 2: ADS1230IPW (MSL 2-260C)								
Package Construction Details								
Assembly Site:	MLA	Mold Compound:	420619	4206193				
# Pins-Designator, Family:	16-PW, TSSOP	Mount Compound:	404250	00				
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wire:	0.96 M	il Dia., Cι	J			
Qualification: Plan	▼ Test Results							
Reliability Test	Conditions	Conditions		Sample Size/Fail				
Reliability Test	Conditions		Lot# 1	Lot# 2	Lot# 3			
**T/C -65C/150C	-65C/+150C (5	-65C/+150C (500 Cyc)		77/0	77/0			
** Thermal Shock -65/150C	-65C/+150C (5	-65C/+150C (500 Cyc)		77/0	77/0			
**High Temp. Storage Bake	170C (420 hrs)		77/0	77/0	77/0			
**Autoclave	121C (384 hrs)	121C (384 hrs)		77/0	77/0			
Manufacturability (Assembly)	(per mfg. Site s	(per mfg. Site specification)		Pass	Pass			
Moisture Sensitivity	(level 2 @ 2600	(level 2 @ 260C peak +5/-0C)		12/0	12/0			
Notes **- Preconditioning s								

Qual Vehicle 3: CDCVF2505PW (MSL 1-260C)							
Package Construction Details							
Assembly Site:	MLA	Mold Compound:	4206193				
# Pins-Designator, Family:	8-PW, TSSOP	Mount Compound:	404250	4042500			
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wire:	0.96 Mil Dia., Cu				
Qualification: Plan Test Results							
Reliability Test	Conditions		Sample Size/Fail				
			Lot# 1	Lot# 2	Lot# 3		
**T/C -65C/150C	-65C/+150C (500 Cyc)		77/0	77/0	77/0		
** Thermal Shock -65/150C	-65C/+150C (500 Cyc)		77/0	77/0	77/0		
**High Temp. Storage Bake	170C (420 hrs)		77/0	77/0	77/0		
**Autoclave	121C (96 hrs)		77/0	77/0	77/0		
Manufacturability (Assembly)	(per mfg. Site specification)		Pass	Pass	Pass		
Moisture Sensitivity	(level 1 @ 260C peak +5/-0C)		12/0	12/0	12/0		
Notes **- Preconditioning sequence: Level 1-260C.							
Qual Vehicle 4: SN75LVDS84ADGG (MSL 2-260C)							
Package Construction Details							
Assembly Site:	MLA	Mold Compound:	4206193				
# Pins-Designator, Family:	48-DGG, TSSOP	Mount Compound: 4042500					
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wire: 0.96 Mil Dia., Cu		J			
Qualification: Plan Test Results							
Reliability Test	Conditions		Sample Size/Fail				
			Lot# 1	Lot# 2	Lot# 3		
**Unbiased HAST	130C/85%RH (192 hrs)		77/0	77/0	77/0		
**T/C -65C/150C	-65C/+150C (500 Cyc)		77/0	77/0	77/0		
** Thermal Shock -65/150C	-65C/+150C (500 Cyc)		77/0	77/0	77/0		
Manufacturability (Assembly)	(per mfg. Site s	(per mfg. Site specification)		Pass	Pass		
Moisture Sensitivity	(level 2 @ 260C peak +5/-0C)		12/0	12/0	12/0		
Notes **- Preconditioning sequence: Level 2-260C.							

Qual Vehicle 5: THS7303PW (MSL 2-260C)							
Package Construction Details							
Assembly Site:	MLA	Mold Compound:	420619	4206193			
# Pins-Designator, Family:	20-PW, TSSOP	Mount Compound:	404250	4042500			
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wire:	0.96 M	0.96 Mil Dia., Cu			
Qualification: Plan Test Results							
Reliability Test	Conditions		Sample Size/Fail				
			Lot# 1	Lot# 2	Lot# 3		
**High Temp. Storage Bake	170C (1000 hrs	170C (1000 hrs)		77/0	77/0		
**Autoclave	121C (384 hrs)	121C (384 hrs)		77/0	77/0		
**T/C -65C/150C	-65C/+150C (500 Cyc)		77/0	77/0	77/0		
** Thermal Shock -65/150C	-65C/+150C (500 Cyc)		77/0	77/0	77/0		
Manufacturability (Assembly)	(per mfg. Site specification)		Pass	Pass	Pass		
Moisture Sensitivity	(level 2 @ 260C peak +5/-0C)		12/0	12/0	12/0		
Notes **- Preconditioning sequence: Level 2-260C.							

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com